Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | KIANIAN ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0122185 A1	07-2003	Wang et al.	257/316
	В	US-2003/0227048 A1	12-2003	Kianian, Sohrab	257/314
	С	US-2004/0191990 A1	09-2004	Kianian et al.	438/257
	D	US-2004/0212009 A1	10-2004	Wang et al.	257/317
	Е	US-2005/0104115 A1	05-2005	Kianian, Sohrab	257/314
	F	US-6,882,572 B2	04-2005	Wang et al.	365/185.18
	G	US-			
	Н	US-			
	_	US-			
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	-				
	0					
	Р			****		
	Q		·			
	R			***		
	s	·				
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wolf, Ph.D., Stanley, Richard N. Tauber, Ph.D, "Thermal Oxidation of Single Crystal Silicon," Silicon Processing for the VLSI Era - Vol. 1: Process Technology, Lattice Press, 1986, page 198.
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.